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U.S. PATENT & TRADEMARK OFFICE

U.S. Department of Commerce, Patent and Trademark <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		Atty. Docket No.	Application No.
		TNCR.007US3	10/619,109
		Applicant(s)	Conf. No.
(Use several sheets if necessary)		Norbert Marxer et al.	5810
		Filing Date	Group
		July 10, 2003	2877

**U.S. Patent Documents**

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
h	1 4,314,763	Feb., 1982	Steigmeier et al.			
h	2 4,360,275	Nov., 1982	Louderbeck			
h	3 4,378,159	Mar., 1983	Galbraith			
h	4 4,391,524	Jul., 1983	Steigmeier et al.			
h	5 4,423,331	Dec., 1983	Koizumi et al.			
h	6 4,479,714	Oct., 1984	Lehrer			
h	7 4,508,450	Apr., 1985	Ohshima et al.			
h	8 4,523,841	Jun., 1985	Brunsting et al.			
h	9 4,526,468	Jul., 1985	Steigmeier et al.			
h	10 4,598,997	Jul., 1986	Steigmeier et al.			

**U.S. Published Patent Application Documents**

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

**Foreign Patent Documents**

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
h	11	614830	Jan., 1988	JP.			Abstract	
h	12	6340004 (3-140g)	Jun., 1988	JP.			Abstract	
h	13	62-85449	Nov., 1988	JP.			Abstract	

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

h	14	"Requirements for Future Surface Inspection Equipment for Bare Silicon Surfaces," P. Wagner and M Brohl, Wacker-Chemitronic GmbH, Burghausen, Germany, W. Baylies, BayTech Group, Weston Massachusetts.
h	15	"The Importance of Media Refractive Index in Evaluating Liquid and Surface Microcontamination Measurements," R. Knollenberg et al., The Journal of Environmental Sciences, Mar./Apr. 1987.
h	16	International Search Report Issued by the International Patent Office (WIPO) corresponding to the International Patent Application No.: PCT/US96/15354 issued on December 27, 1996.

Examiner RAD Date Considered 4/29/05

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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<i>m</i>	17	4,735,504	Apr., 1988	Tycko.			
<i>m</i>	18	4,744,663	May., 1988	Harnashima et al.			
<i>m</i>	19	4,893,932	Jan., 1990	Knollenberg.			
<i>m</i>	20	5,076,692	Dec., 1991	Neukermans et al.			
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<i>m</i>	22	5,189,481	Feb., 1993	Jann et al.			
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<i>m</i>	24	5,315,609	May., 1994	Tanaka et al.			
<i>m</i>	25	5,377,001	Dec., 1994	Malin et al.			
<i>m</i>	26	5,377,002	Dec., 1994	Malin et al.			
<i>m</i>	27	5,389,794	Feb., 1995	Allen et al.			
<i>m</i>	28	5,406,367	Apr., 1995	Sopori.			
<i>m</i>	29	6,178,257	Jan., 2001	Alumot et al.			

**U.S. Published Patent Application Documents**

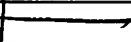
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